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TECHNICAL MEMORANDUM 1891

RELY,  
 A PROGRAM FOR ESTIMATING  
 OVERALL SYSTEM RELIABILITY BASED ON  
 COMPONENT, SYSTEM AND  
 FLIGHT DATA

THOMAS A. NEEF

MARCH 1969



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PICATINNY ARSENAL  
DOVER, NEW JERSEY

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A PROGRAM FOR ESTIMATING  
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DATA PROCESSING SYSTEMS OFFICE  
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## ABSTRACT

This report documents a program for estimating overall system reliability by judiciously combining individual component data, laboratory test data and finally flight data as gathered at two different periods in time. All data used in arriving at this single reliability estimate is assumed to be attribute in nature.

## INTRODUCTION

In July 1968, the Munitions Command requested the Mathematical Analysis Division of the Data Processing Systems Office to develop a computer program (using their prescribed methodology) to estimate overall system reliability. Such a program has been created, herein called RELY, which requires as input six sets of distinct attribute type data which should commonly arise during the development phase of a missile assembly or subassembly program. The six sets of basic inputs consist of the three types of data listed below gathered at two distinct time periods:

- (1) Component data as naturally arising from individual component tests.
- (2) Laboratory systems data arising from testing a component assembly (i.e. circuit) in a laboratory and
- (3) Flight data consisting of data resulting from actual test firings containing all circuitry.

The program judiciously combines this data so as to produce a single estimate for overall system reliability.

This report describes in detail this computer program and includes a complete description of input-output formats, a discussion of the program logic and a sample case. It should be emphasized however, that this report does not describe the foundations of the methodology utilized. For this the interested reader is referred to Reference 1.

## GENERAL PROGRAM OUTLINE

To simplify the discussion the following mathematical notation has been adopted.

### Mathematical Notation:

$A_{ij}$              $A = N$  refers to number of tests conducted at  $i$  th stage at time  $T_j$

(basic inputs)     $A = C$  refers to number of successes resulting from testing at the  $i$  th stage at time  $T_j$

### Subscript definition:

$i = c$  (Component stage) refers to component data .

$i = s$  (System stage) refers to system data, i.e.

resulting from testing circuits comprised of the above components

$i = f$  (flight stage) refers to flight data, i.e.

resulting from flight tests containing the circuitry above

$j = 0$  refers to time  $T_0$

$j = 1$  refers to time  $T_1$  where  $T_0 < T_1$

Thus  $N_{s_1}$  refers to the number of systems tests conducted at time  $T_1$ ,

while  $C_{f_0}$  refers to the number of flight successes obtained at time  $T_0$ .

$K_i$             refers to a weighting factor that weights the less significant  $T_0$  data when combining with  $T_1$  data.  $i$  again refers to component ( $i=c$ ), systems ( $i=s$ ) or flight ( $i=f$ ) data.

$A_{ieq}$

refers to the equivalent number of tests ( $A=N$ ), or equivalent number of successes ( $A=C$ ) for either component, system or flight data, ( $i=c, s, f$  respectively). These values arise by appropriate combination of  $N_{co}, C_{co}, N_{c1}, C_{c1}, K_c$  to obtain  $N_{ceq}$  and  $C_{ceq}$ , or more generally by combination of  $A_{io}, A_{i1}$  and  $K_i$ , to produce  $A_{ieq}$ .

$K_{ieq}$

refers to the weight given to the equivalent component data, when combining with the equivalent system data ( $i=s$ ), to produce combined component-system data. When  $i=f$ , this variable refers to the combination of the component-system data with the equivalent flight data to produce the overall equivalent number of tests  $N_{eq}$  and overall equivalent number of successes  $C_{eq}$  used to arrive at  $P_{best}$ .

$P_{best}$

refers to the overall system reliability =  $C_{eq}/N_{eq}$

The interrelationships existing between the various data sets are exhibited in Figure 1. Figure 2 is a schematic diagram showing the relative significance of the involved data sets.

The underlying approach to arrive at  $P_{best}$ , the single estimate

of overall reliability, is to combine all like data sets, degrading however, the less significant  $T_0$  data, when combining with the more significant  $T_1$  data. Similar degradation factors apply when combining the less significant equivalent component data, with the more significant equivalent system data and the more significant, yet, flight data.

Each such combination of data will be described, thus yielding in the process a general program outline.

I. Combination of component data  $N_{co}, C_{co}, N_{c1}, C_{c1}$  to produce  $N_{ceq}, C_{ceq}$ .

A. One component case.

Here  $N_{co}, C_{co}, N_{c1}, C_{c1}$  embody the inputs to this calculation. The values for the above are obtained from actual testing, witnessing for example  $C_{co}$  success out of  $N_{co}$  tests at time  $T_0$ .

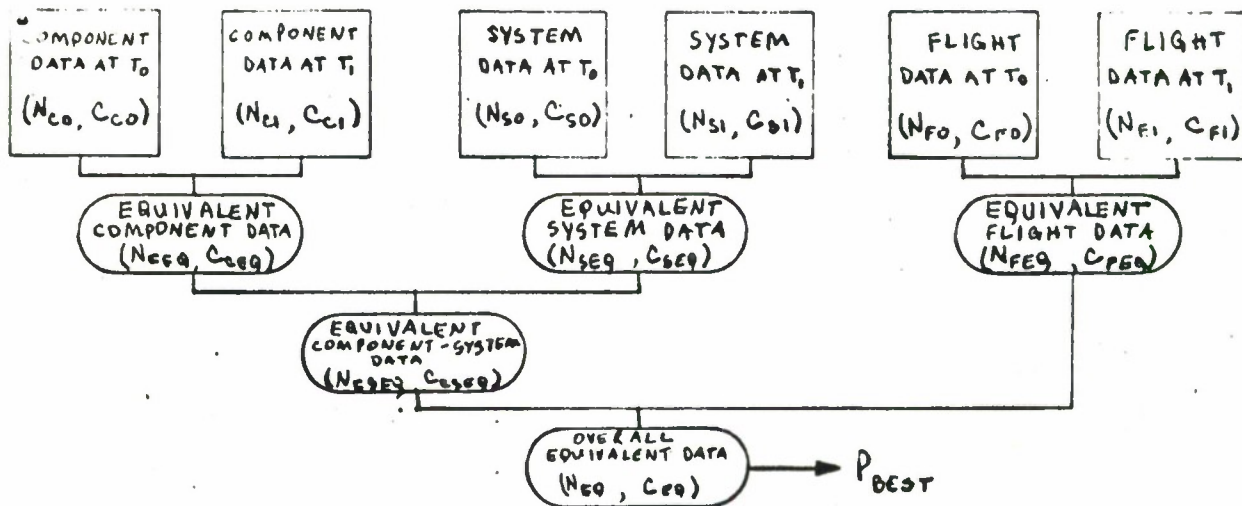


FIGURE 1



It is assumed that  $P$ , the true probability of component functioning is  $\beta$ -distributed with  $N_{co}$ ,  $C_{co}$  as parameters, i.e.

$$\beta_o(P) = \frac{\Gamma(N_{co} + 2)}{\Gamma(C_{co} + 1) \Gamma(N_{co} - C_{co} + 1)} P^{C_{co}} (1-P)^{N_{co} - C_{co}} \quad (1)$$

with a similar expression  $\beta_1(P)$  for components tested at time  $T_1$ . The  $T_0$  data is degraded by the area,  $K_c$ , common to the two  $\beta$ -distributions, as expressed in the following equations that yield the equivalent component data.

$$N_{ceq} = N_{co} \cdot K_c + N_{c1}; \quad C_{ceq} = C_{co} \cdot K_c + C_{c1} \quad (2)$$

$K_c$  is interpreted geometrically in the Diagram below

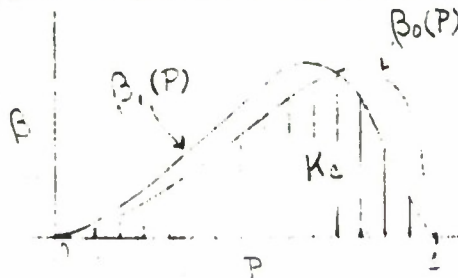


DIAGRAM 1

Thus if  $N_{co} = N_{c1}$  and  $C_{co} = C_{c1}$  the two distributions would coincide and the degradation factor would be 1 (i.e. no degradation).

#### B. Several Component case.

When several different component types are involved and related by a specific circuit equation, calculations additional to those above are necessary. In this case it is required to compute a  $N_{ceq}$  and  $C_{ceq}$  for each component type and combine the results. Let  $N_{ceq}(k)$  and

$C_{ceq}(k)$  represent the above values referred to the k-th component type.

An equation similar to equation (1) is constructed with these values

i.e.

$$\beta(P,k) = \frac{\Gamma(N_{ceq}(k) + 2)}{\Gamma(C_{ceq}(k) + 1) \Gamma(N_{ceq}(k) - C_{ceq}(k) + 1)} Q \quad (3)$$

where

$$Q = P^{C_{ceq}(k)} (1 - P)^{N_{ceq}(k) - C_{ceq}(k)}$$

This represents the probability density  $P$  of the k-th component type in the light of both  $T_0$  and  $T_1$  data. The calculation to combine each  $N_{ceq}(k)$  and  $C_{ceq}(k)$  to produce  $N_{ceq}$  and  $C_{ceq}$  then proceeds in a Monte Carlo fashion involving the circuit.

Values are sampled from each of the  $\beta$ -distributions\* and inserted into the specified circuit equation, from which the probability of circuit functioning,  $R_s$  for these values, is obtained. It is important to note that if a given component type appears several times in the circuit, the corresponding  $\beta$ -distribution is sampled only once per simulation. Performing this simulation  $M$  times thus yields  $M$  values for the probability of circuit functioning. The assumption is made that these  $M$  values are  $\beta$ -distributed. Consequently the mean  $\mu$ , and the variance  $\sigma^2$  of these numbers are computed and set equal to the mean and variance of the  $\beta$ -distribution.

---

\*This is accomplished by numerically determining the cumulative distribution and finding the  $P$  corresponding to  $RN = \int_0^1 \beta(k,X) dX$  where  $RN$  is a random number between 0 and 1. The integral is tabulated as a function of  $P$ , so that for given  $RN$ , linear interpolation applies for ascertaining  $P$ .

This allows for the two unknown parameters in this distribution to be solved. These unknowns correspond in fact to the  $N_{ceq}$  and  $C_{ceq}$  of Figure 1. Mathematically, this procedure is equivalent to the equations that follow.

$$\mu = \frac{\sum_{i=1}^M R_S(i)}{M} \quad \sigma^2 = \frac{\sum_{i=1}^M R_S^2(i) - 2\mu \sum_{i=1}^M R_S(i) + M\mu^2}{M} \quad (4)$$

$$N_{ceq} = \frac{\mu(1-\mu) - 3}{\sigma^2} \quad C_{ceq} = \frac{\mu^2(1-\mu) - (1+\mu)}{\sigma^2} \quad (5)$$

II. Combination of system data  $N_{so}$ ,  $C_{so}$ ,  $N_{s1}$ ,  $C_{s1}$  to produce  $N_{seq}$  and  $C_{seq}$ ,

This combination is accomplished analogously to equations (1) where the degradation factor is again the area common to the two distributions. Thus

$$\beta_0(P) = \frac{\Gamma(N_{so} + 2)}{\Gamma(C_{so} + 1) \Gamma(N_{so} - C_{so} + 1)} P^{C_{so}} (1-P)^{N_{so} - C_{so}}$$

$$\beta_1(P) = \frac{\Gamma(N_{s1} + 2)}{\Gamma(C_{s1} + 1) \Gamma(N_{s1} - C_{s1} + 1)} P^{C_{s1}} (1-P)^{N_{s1} - C_{s1}}$$

$$K_s = \int_0^1 \text{Min}\{\beta_0(P), \beta_1(P)\} dP \quad (6)$$

$$N_{seq} = N_{so} \cdot K_s + N_{s1}$$

$$C_{seq} = C_{so} \cdot K_s + C_{s1}$$

III. Combination of flight data  $N_{fo}$ ,  $C_{fo}$ ,  $N_{f1}$ ,  $C_{f1}$  to produce  $N_{feq}$ ,  $C_{feq}$ .

This again is completely analogous to II with  $N_{so}$ , ...,  $C_{s1}$  replaced by  $N_{fo}$ , ...,  $C_{f1}$  respectively.

IV. Combination of equivalent data produced in I, II, and III to produce  $N_{eq}$ ,  $C_{eq}$ .

The combination of  $N_{ceq}$ ,  $C_{ceq}$  with  $N_{seq}$ ,  $C_{seq}$  to produce  $N_{c,seq}$ ,  $C_{c,seq}$  and the combination of these last two values with  $N_{feq}$ ,  $C_{feq}$  to produce  $N_{eq}$ ,  $C_{eq}$  are also completely analogous to II with the  $A_{ceq}$  replacing the  $A_{so}$  and the  $A_{seq}$  replacing the  $A_{s1}$  in the first case and the  $A_{c,seq}$  replacing the  $A_{so}$  and the  $A_{feq}$  replacing the  $A_{s1}$  in the second case. Thus the last equation in (6) becomes  $C_{c,seq} = C_{ceq} \cdot K_{seq} + C_{seq}$  when combining components and system data, and becomes  $C_{eq} = C_{c,seq} \cdot K_{feq} + C_{feq}$  when combining component-systems data with flight data.

V. Calculation of overall system reliability,  $P_{best}$ .

$$P_{best} = \frac{C_{eq}}{N_{eq}} \quad (7)$$

For output purposes, the following two variable are also computed by the equations that follow

$$\mu = \frac{C_{eq} + 1}{N_{eq} + 2} \quad \text{VARIANCE} = \frac{(C_{eq} + 1)(N_{eq} - C_{eq} + 1)}{(N_{eq} + 2)^2 (N_{eq} + 3)} \quad (8)$$

## COMPUTER PROGRAM DESCRIPTION

### A. Description of MAIN program

This Section describes the computer program that evaluates the mathematical model. It is believed that sufficient information is contained herein along with COMMENT statements in the program listing to enable one to understand and possibly modify the program. Figure 3 is an overall flow chart giving the sequence of the computations. Not shown in the figure is the fact that much of the routine calculations such as the tabulation of the  $\beta$ -distribution, numerical integration etc. are relegated to subroutines. These subroutines though briefly referred to in the text are more fully described at the end of this Section.

All inputs are read in the MAIN program, thereupon one set of component data is selected, being the values for N and C at time  $T_0$  and values for N and C at  $T_1$ . Using these four values (labelled in the program as NCO, CCO, NCL, CCL respectively) as input arguments the value KA ( $=K_c$  of Diagram 1) is ascertained from a subprogram K. The  $T_0$  data is then degraded by this factor and the result added to the  $T_1$  data to yield two new intermediate values, SUB1, corresponding to the number of trials and SUB2 corresponding to the number of successes as in equation (2) (page 7). Using these intermediate values as parameters a  $\beta$ -distribution (corresponding to equation 3) is constructed and tabulated in subroutine BETAF. The tabulation is effected at equally spaced abscissas depending upon the value of DELTAP which should lie

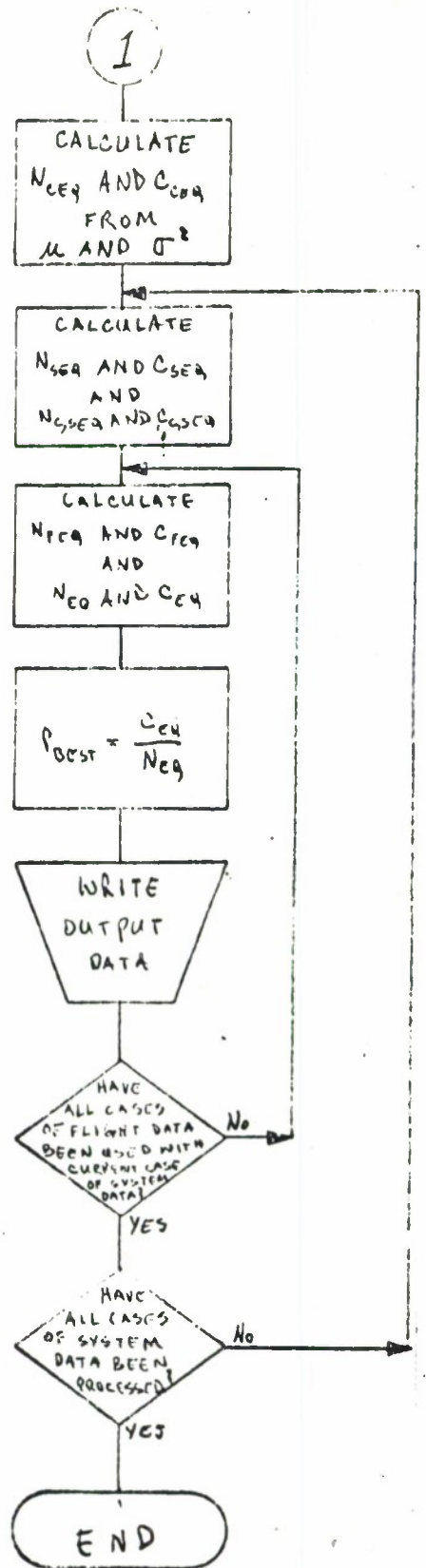
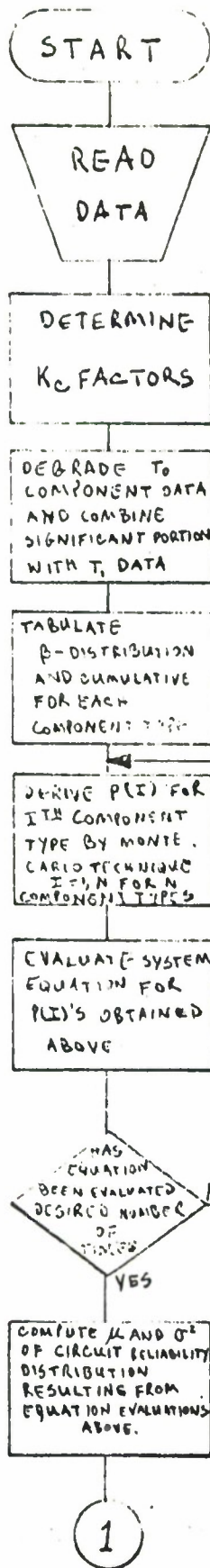


Figure 3

in the interval [.01, .5]. It is from this density function that the probability of component functioning is sampled and subsequently inserted into the circuit equation. To accomplish this, the cumulative of this distribution is tabulated and placed in an array A(I) (subroutine DQSF), a random number, (RDM(1)), selected and the corresponding P value determined by linear interpolation in subprogram INTERP. This calculation is repeated for each component type, and all results are ultimately substituted into the circuit equation from which a probability of circuit functioning, (RS), is computed. At this point a running count of these RS values for output purposes in histogram form is maintained, along with running summations of the RS values and  $RS^2$  values for use in calculating the mean  $\mu$  and variance  $\sigma^2$  of these generated numbers (equations 4). At the end of the simulation loop, equations (5) are used to produce  $N_{ceq}$  and  $C_{ceq}$  which are labelled as NCEQ and CCEQ in the program. Remaining calculations involving system and flight data, and all combinations thereof are analogous to what has been described and again typically involve use of the BETAF and K routines. The notation, too, in remaining segments of the MAIN program is quite suggestive so that the reader will find for example  $N_{so}$ ,  $C_{seq}$ , and  $P_{best}$  are represented in the program as NSO, CSEQ and PBEST.

## B. Description of Subprograms (in alphabetical order)

### 1. FUNCTION AREAF (B,J)

Common DELTAP

Description of arguments:

B - one-dimensional equidistantly tabulated function the area under which is to be computed.

J - the number of values in B.

DELTAP - interval width

Operation:

Calculates the area under B by Simpson's rule, (therefore J must be odd). The output is a scalar representing the area under the curve.

## 2. SUBROUTINE BETAF (N, C, BETA, J, PB)

Common DELTAP

Description of arguments:

Input Arguments:

N,C - input parameters for the beta-distribution equation

Output Arguments:

BETA - one dimensional beta-distribution array produced in the subroutine

J - number of values in array (dependent upon DELTAP)

PB - one dimensional array of P-values used in generating the beta distribution

DELTAP - interval width

Operation:

Produces an equidistantly tabulated beta-distribution

using the following equation:

$$\beta = G P^C (1 - P)^{N - C} \quad (9)$$

where G is a constant,

$$G = \frac{\Gamma(N + 2)}{\Gamma(C + 1) \Gamma(N - C + 1)} = \frac{(N+1)!}{C!(N-C)!} \quad (10)$$

and is computed in subroutine GAMA, P varies from 0.0 to 1.0 in increments of DELTAP

In order to avoid problems arising from zero bases and/or zero exponents in the exponentiation routine, the equation is evaluated for one of four cases as:

1. N and C are distinct and nonzero.
2. N and C are identical and nonzero.
3. N is nonzero but C is zero.
4. Both N and C are zero.

### 3. SUBROUTINE DQSF (H, Y, Z, NDIM)

This subprogram is part of the IBM System/360 SCIENTIFIC SUBROUTINE PACKAGE and a detailed description of its arguments and operation can be found therein. Briefly, however, this subroutine performs the integration of an equidistantly tabulated function by Simpson's Rule. It computes a vector of integral values  $Z_i$  for a table of functional values  $Y_i$ ,  $i= 1, 2, \dots, N$  given at equidistant points  $X_i = a + (i-1)h$

$$Z_i = Z(X_i) = \int_a^{X_i} Y(X) dx \quad (i= 1, 2, 3, \dots, N)$$

#### 4. FUNCTION GAMA (ARG1, ARG2, ARG3)

Description of arguments:

ARG1 - corresponds to N+2 in equation (10) of subroutine  
BETAF

ARG2 - corresponds to C+1 in equation (10) of subroutine  
BETAF

ARG3 - corresponds to N-C+1 in equation (10) of subroutine  
BETAF

Operation:

The IBM - supplied subroutine GAMMA evaluates the GAMMA function for a given argument provided the argument is less than or equal to 57. The subroutine GAMA is designed to reduce each of the arguments ARG1, ARG2, ARG3, to 57, if necessary, before calling GAMMA for each of them.

Furthermore it computes G

$$G = \frac{\Gamma(\text{ARG1})}{\Gamma(\text{ARG2}) \Gamma(\text{ARG3})} \quad (11)$$

for use in subroutine BETAF. Output is scalar value for G.

#### 5. SUBROUTINE GAMMA (XX, GX, IER)

This subroutine is part of the SCIENTIFIC SUBROUTINE PACKAGE except that was changed to double precision for this program. Briefly the operation of this subroutine is to evaluate the gamma function for a given value of XX, where  $\Gamma(X)$  is defined for  $X > 0$  by

$$\Gamma(X) = \int_0^{\infty} t^{X-1} e^{-t} dt$$

which satisfies the recurrence relation  $\Gamma(X) = (X-1)\Gamma(X-1)$

which defines  $\Gamma(X)$  for any  $X$  non-negative integer i.e.

$$\Gamma(X) = (X-1)!$$

6. FUNCTION INTERP (I, J, F, YFL)

Common /BLKL/AX

Description of arguments:

I - component type designation

J - number of values in ITH row of two-dimensional array  
AX corresponding to array AREA of the MAIN program, in  
which the scalar input YFL will be interpolated.

F - the one-dimensional array from whose elements the  
interpolated value is to be calculated.

YFL - number whose corresponding value is to be found by  
interpolation

AX - subroutine name for array AREA of MAIN program which  
stores cumulative for each component type.

Operation:

Straight-forward linear interpolation is effected herein.

7. FUNCTION K (NO, CO, N1, C1)

Common DELTAP

Description of arguments

NO, CO - number of trials and number of successes at time  
 $T_0$  (or analogous parameters)

N1, C1 - number of trials and number of successes at most recent testing  $T_1$  (or analogous parameters)

DELTAP - interval width

Operation:

K is designed to produce a proportionality factor for degrading the less significant data, NO, CO (before it is combined with the more significant data N1, C1 in MAIN program). This is accomplished by first tabulating the beta-distributions for NO, CO and for N1, C1 by calling subroutine BETAF. The area under the intersection of these two curves, CMAREA, is found next by comparing the two beta curves point-for-point, in each case taking the smaller of the two values (ordinates), putting it into a new array, and computing the area under this curve in subroutine AREAF. AREAF is also used to find the area, TIAREA, under the beta curve for the most significant data N1, C1 (this area should be close to or exactly equal to 1.0 and is computed and used as a self adjusting calculation to account for digital round-off error). K is then set equal to CMAREA divided by TIAREA. The output of this subroutine is the scalar significance factor, K.

## PROGRAM OPERATION

This Section describes the inputs necessary to run the program RELY as well as a description of the output variables. To allow for the desirability of analyzing several different system and/or flight data sets for a given set of component data, the inputs have been so arranged to facilitate these additions with a minimum of card entries. One may note, further, that since the bulk of the calculations are concerned with component data, additional results depending on varying system or flight data sets require only a small investment of computer running time for the added evaluation.

To operate the program RELY the probability equation for the circuit must be inserted into the program between the COMMENT statements MATH MODEL-BEGIN and MATH MODEL-END (see program listing). In doing this one should number each component type in any convenient manner so that a correspondence exists between the component test results and the same component in the circuit. An example for a simple circuit is contained in the sample inputs. In addition values for the variables listed below must be supplied in the format indicated, as well as the actual component, system and flight input data.

<u>VARIABLE</u>	<u>DESCRIPTION</u>	<u>FORMAT</u>
T	Time between testing dates (months).	I2
NRS	Number of times the circuit equation is to be evaluated (NRS>1) i.e. number of Monte Carlo simulations, limited only by format size and computer running time.	I6

<u>VARIABLE</u>	<u>DESCRIPTION</u>	<u>FORMAT</u>
DELTAP	( $\Delta P$ ) Desired increment on P-values in setting up Beta-distributions and reliability distribution ( $.01 \leq \Delta P \leq .5$ )	F6.4
NCOMP	Number of distinct component types in the circuit ( $1 \leq NCOMP \leq 100$ )	I4
NSYDT	Number of system data sets to be used with a given set of component data ( $1 \leq NSYDT \leq 100$ )	I4
NFLDT	Number of flight data sets to be used in conjunction with the given component data set ( $1 \leq NFLDT \leq 100$ )	I4

Values for these six variables form the first card of the data deck. This card is followed by: the component data set, which contains one card for each component type, the laboratory system data set and finally the flight data set. Each card of each set has the same format (4I6). The four values on these cards are  $N_{i0}$ ,  $C_{i0}$ ,  $N_{i1}$ ,  $C_{i1}$  in that order. The first card of the component data set must contain the data corresponding to the first component as labelled in the circuit equation, the second card contains data for component 2, and so forth for all component data.

All data cards of the system and flight data sets are set up exactly like those of the component data set, the order of cards within each set being entirely arbitrary. All combinations of system and flight data, will be evaluated when  $NSYDT > 1$  and  $NFLDT > 1$ , all cases of flight data being combined in turn with each case of system data. The program may be run without system and/or flight data. In this case  $NSYDT$  and/or  $NFLDT$  must be set equal to 1, and the appropriate data set must

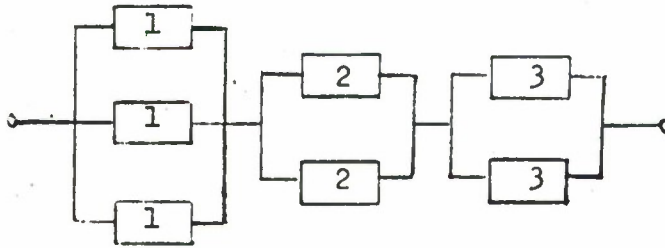
consist of one blank card.

For a description of the output of program RELY, refer to the sample case, page 25.

### SAMPLE CASE

As a sample case consider the simple circuit configuration below.

It consists of seven components but only three distinct component types: type 1, type 2, type 3.



The probability equation for this circuit is

$$R_s = (1 - (1 - P(1))^3) (1 - (1 - P(2))^2) (1 - (1 - P(3))^2)$$

where  $P(i)$  is the probability of component type  $i$  functioning properly.

Typical input data for this circuit is presented in the table on the next page. It will be noted, for example, that components of type 2 worked satisfactorily 42 times out of 44 trials during the first round of testing ( $T_0$ ) but twenty four months later ( $T_1$ ), worked only 38 times in 44 trials.

In order to compute an estimate of overall system reliability for this circuit based on the data compiled in the following table using program RELY it is necessary to:

1. Insert the circuit equation into the program between the comment cards MATH MODEL - BEGIN and MATH MODEL - END (See Listing which contains this example).

	FIRST ROUND OF TESTING (TIME T <sub>0</sub> )		SECOND ROUND OF TESTING (TIME T <sub>1</sub> )	
	<u>Number of trials</u>	<u>Number of successes</u>	<u>Number of trials</u>	<u>Number of successes</u>
COMPONENTS:				
TYPE 1	66	57	66	54
TYPE 2	44	42	44	38
TYPE 3	44	40	44	35
LABORATORY SYSTEM DATA:				
FIRST CASE	22	22	22	22
SECOND CASE	22	22	22	18
FIELD SYSTEM DATA (only one case was used for this particular run)	4	4	4	3

Input Data  
for  
Sample Case

2. Set up a data deck consisting of (refer to fig. 4):

a. One card containing 6 input parameters.

	<u>Columns</u>	<u>Value</u>	
T	1-2	24	It is assumed twenty four months elapsed between the two rounds of testing. (T used only for printout).
NRS	3-8	10000	Number of simulations. Here the circuit equation will be evaluated 10,000 times in determining $N_{ceq}$ , $C_{ceq}$ .
DELTAP	9-14	.01	$\Delta P$ - Increment on P This will cause the Beta-distributions and reliability histogram to be formed in steps of .01 along the horizontal-axis, P.
NCOMP	15-18	3	Number of distinct component types. There are three distinct types of components in this circuit even though there is a total of seven components.
NSYDT	19-22	2	Number of cards in the system data set. Since there are two cases of laboratory system data, there must be two data cards in the system data set, as governed by this 2.
NFLDT	23-26	1	Number of cards in flight data set. For this particular run there is only one case of flight data and consequently there is only card in the flight data set.



b. Component Data Set - consists of three data cards, one for each of the three distinct component types in the sample circuit. Card 1 contains the data for the component type labeled #1 in the circuit diagram and circuit equation; card 2 contains the data for component type 2; and card 3 contains data for component type 3. This correspondence between component numbering in the circuit diagram and circuit equation and the ordering of cards in the data deck is essential, however the initial assignment of numbers to the different component types in the circuit is completely arbitrary. Each card in this data set contains the appropriate four values taken from the table of test results above. For example, card 1 contains the number of trials 66 and corresponding number of successes, 57, for component 1 from the first round of testing at time  $T_0$ , followed by the test results from round two, time  $T_1$ : 66, 54. The numbers are typed in the first 24 columns (6 columns per number, right-adjusted format-4I6).

c. System Data Set - consists of two data cards: one for each of the two cases of laboratory system tests. For example, the first card in this set contains the results of the first case compiled during the first round of tests, time  $T_0$  - 22 trials, 22 successes, followed by those of the second round of tests, time  $T_1$  - 22 trials, 22 successes. The format of the cards in this set is identical to that of the cards in the component data set.

d. Flight Data Set - this data is set up exactly like the previous two sets except that the data are the results of testing the

system in the field.

The output of program RELY as exhibited in the output listing of the sample case, Figure 5, consists of a listing of the input values in tabular form which shows the order in which the system and flight data are evaluated. The system reliability histogram showing the distribution of the  $R_s$  values calculated from the circuit equation is exhibited next. The mean and variance are also printed from which  $N_{ceq}$  and  $C_{ceq}$  are computed. Finally the calculated values for all the  $A_{ieq}$  and intermediate variables as well  $P_{best}$ ,  $\mu$  and Variance for all cases of system and flight data combinations are listed. The printout of the histogram begins with the line preceeding the first appearance of a non-zero element in the distribution. For example, in the output of the sample case, the smallest  $R_s$  value computed in the 10,000 simulations fell in the range  $.77 < R_s \leq .78$ , so the first line printed was for  $P = .77$ .

LAB COMPONENT INPUT DATA

$T = T1 - T0 = 24$

COMPONENT	T0		T1	
	N	C	N	C
1	66	57	66	54
2	44	42	44	38
3	44	40	44	35

SYSTEM AND FLIGHT INPUT DATA

CASE #	TO		TI	
	SYSTEM N	FLIGHT C	SYSTEM N	FLIGHT C
1	22	4	22	4
2	22	4	18	4

RELIABILITY HISTOGRAM FOR EQUIVALENT-SYSTEM FOR COMPONENTS

P	
C.77C	0
C.78C	1
C.79C	0
C.80C	2
C.81C	1
C.82C	4
C.83C	3
C.84C	18
C.85C	34
C.86C	37
C.87C	90
C.88C	158
C.89C	283
C.90C	488
C.91C	760
C.92C	1132
C.93C	1511
C.94C	1774
C.95C	1820
C.96C	1318
C.97C	498
C.98C	67
C.99C	1
1.00C	

DISTRIBUTION

MEAN = 0.93930 D 0C  
 VARIANCE = C.54983 D-03

FIGURE 5

NUMBER OF SIMULATIONS = 10000

CASE # 1 NCEQ = 100.68544 CCEQ = 95.45660 ASEQ = 44.00000 CSEC = 44.00000 ACSEQ = 76 82919 CCSEQ = 75.12305  
NEQ = 6.36160 CFEQ = 5.36160 NEQ = 17.40282 CEC = 16.15763  
PBEST = 0.92E45 MU = 0.8E429 VARIANCE = 0.00502

CASE # 2 NCEQ = 100.68544 CCEQ = 95.45660 ASEQ = 25.53925 CSEC = 21.53925 ACSEQ = 43 85685 CCSEQ = 38.90488  
NEQ = 6.36160 CFEQ = 5.36160 NEQ = 28.87628 CEC = 25.33410  
PBEST = 0.87733 MU = 0.8E289 VARIANCE = 0.00394

REFERENCE

1. Naval Ammunition Depot, Oahu, Hawaii, 21 January 1969, "A Proposed Tri-Service Approach for Reliability Assessment", Appendix D.

APPENDIX I



```

INF1(J),CF1(J)
3 DO 104 I=1,NCCMF
  VC = AC0(I)
  CC = CC0(I)
  NI = NC1(I)
  CI = CC1(I)
  KA = K(INC,CO,NI,CI)
  SU91 = NC*KA + NI
  SU12 = CC*KA + CI
C
C SETUP COMPONENT RELIABILITY HISTOGRAM FOR ITH COMPONENT
C
C CALL 3GTAF(SUR1,SUR2,BETA,J,PR)
C
C CALL SUBROUTINE TO PRODUCE CUMULATIVE FOR ITH COMPONENT
C
C CALL DCSFIDELTAP,BETA,A,J)
C
C PUT THE VECTOR, A, OF INTEGRAL VALUES PRODUCED IN THE SUBROUTINE FOR THE ITH
C COMPONENT INTO THE ITH ROW OF THE AREA ARRAY.
C
DO 104 N=1,J
  104 AREAT(N) = A(N)
C
C INITIALIZE STORAGE AREAS AND VARIABLE LOCATIONS.
C
DO 105 M = 1,J
  105 DISTIM = 0
  SMPS = 0.0
  SMRSSC = 0.0
  NCF0 = 0.0
  CCF0 = 0.0
  RMSMEAN = 0.0
  VAR = 0.0
  IJ = J
C
C BEGIN MOUNTAIN CARLC PROCESS WITH WHICH TO DEVELOP THE EQUIVALENT-SYSTEM
C RELIABILITY DISTRIBUTION FOR COMPONENTS
C
DO 111 L=1,ARS
  RS = 0.0
DO 107 I=1,NCCMF
  YFL = RDM(I)*AREAT(I,J)
C
C THE RANDOM NUMBER SELECTED FOR THE ITH COMPONENT IS MULTIPLIED BY THE
C LARGEST VALUE IN THE APPROPRIATE CUMULATIVE AS A SELF-ADJUSTING
C CALCULATION TO ACCOUNT FOR DIGITAL ROUNDOFF ERROR
C
107 P(I) = INTERP(I,J,PR,YFL)
C
C *****
C MATH MODEL - BEGIN
  RS = (1.0-(1.0-P(I))**3)*(1.0-(1.0-P(2))**2)*(1.0-(1.0-P(3))**2)
C MATH MODEL - END
C *****

```

```

117 SMRS = SMRS + RS
118 SMRSSC = SMRSSC + RS**2
119 SAVE = L
120
121 C SET UP RELIABILITY DISTRIBUTION, DIST(M)
122 C
123 M = J + 1
124 M = M - 1
125 IF (1.0 - QS .LT. DELTAP) GC TC 108
126 IF (PR(M) - RS) 13,14,12
127 14 IF (QS .GT. C.C .CR. RS .EG. 1.0) GC TC 108
128 M = M + 1
129 ICP DIST(M) = DIST(M) + 1
130 IF (M .LT. IJ) (J=M
131 CONTINUE
132 IJ=IJ-1
133 WRITE (4,250)
134 WRITE (6,203) ((PR(JJ), DIST(JJ)), JJ=1J,J)
135 RSMEAN = SMRS/SAVE
136 VAR = (SMRSSC - 2.0*RS*FAN*SMRS + RSMEAN**2*SAVE)/SAVE
137 WRITE (6,210) RSMEAN, VAR
138 WRITE (4,250)
139 WRITE (6,214) NRS
140 IF (VAR) 51,51,16
141 X = RSMEAN
142
143 C COMPUTE A-EQUIVALENT AND C-EQUIVALENT FOR COMPONENTS
144 C
145 CCEO = (X**2*(1.0 - X))/VAR - (1.0 + X)
146 MCEO = X*(1.0 - X)/VAR - 3.0
147 NCASF = 0
148
149 C DEVELOP EQUIVALENT SYSTEM FOR LAE SYSTEM DATA AND COMBINE IT WITH
150 C EQUIVALENT SYSTEM FOR LAB COMPONENT DATA, YIELDING C,S EQUIVALENT SYSTEM
151 C
152 DO 112 I=1,NSYDT
153 MC = NSO(I)
154 CC = CSO(I)
155 NI = NSI(I)
156 CI = CSI(I)
157 NSEQ=C.O
158 CSEQ=C.O
159 MCSFO=C.O
160 CCSFDC=O
161 IF (NC .EG. 0.0 .AND. NI .EG. 0.0) GC TO 114
162 KA = K(NG,CO,NI,CI)
163 NSEQ = NI + NO*KB
164 CSEQ = CI + CC*KB
165 KC = X(NCEG,CCEG,NSEC,CSEC)
166 KSE = 1.0
167 KSEPRM = 1.0
168 NCSEQ = KSE*NSEC + KSEPRM*MC*NSEC
169 CCSEQ = KSE*CSEC + KSEPRM*MC*CSEC
170
171 C DEVELOP EQUIVALENT SYSTEM FOR FLIGHT DATA AND COMBINE IT WITH C,S
172 C EQUIVALENT SYSTEM, YIELDING FINAL EQUIVALENT SYSTEM REFLECTING ALL SIGNIFICANT
173 C DATA FROM WHICH THE BEST ESTIMATE OF SYSTEM RELIABILITY, PREST, IS COMPUTED
174 C

```

CARD  
NUMBER

```

175 00 113 V=1,NEQ1
176 NC = A*(M)
177 CC = C*(M)
179 NI=NI*(M)
180 CIECI(M)
181 NFEQ=C*Q
182 CFEQ=C*Q
183 NFEQ=C*Q
184 CFEQ=C*Q
185 VLR=C
186 VLR=C
187 IF(NC .EQ. 0.7 .AND. NI .EQ. 0.0) GO TO 110
188 KQ = K*(AD*CC*AI,CI)
189 NFEQ = NI + KQ*NC
190 CFEQ = CI + KQ*CC
191 KQ = K*(AD*CC*CC*CC*CFEQ)
192 NFEQ = NFEQ + KQ*NCSEC
193 CFEQ = CFEQ + KQ*CCSEC
194 NFEQ = CFEQ/NEQ
195 NFEQ = (CFC + 1.)/(NEQ + 2.)
196 NFEQ = (CFC + 1.)/(NEQ - CFC + 1.)/((NEQ + 2.)*2*(NEQ + 3.))
197 NCASE = NCASE + 1
198 WRITE (5,250)
199 WRITE (5,213) NCASE,NCFC,CCFC,NSEC,CSEC,NCSEC,CCSEC,NFEQ,CFEQ,NEQ,
200 CFEQ,PREST,ML,VRN
201 113 CONTINUE
202 GO TO 1
203 50 WRITE (4,207)
204 GO TO 52
205 51 WRITE (3,208)
206 CALL EXIT
207 END
208
209
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```

FUNCTION AREA(F,P,J)

PURPOSE  
TO CALCULATE THE AREA UNDER A CURVE BY SIMPSON'S RULE.

DESCRIPTION OF ARGUMENTS  
A - CAR-OR-MENSURAL EQUIDISTANTLY TABULATED FUNCTION THE  
AREA UNDER WHICH IS TO BE COMPUTED.  
J - THE NUMBER OF VALUES IN B.

DOUBLE PRECISION FUNCTION AREA(F,P,J)  
DOUBLE PRECISION A(I), DELTAP, CFC,EVEN  
COMMON DELTAP  
M=1  
EVEN = 1.0  
L = J-1  
DO 100 I=2,L,2  
EVEN = EVEN + 1(I)  
100 A(I) = (A(I) + A(I+1))  
AREA = (DELTAP/3.0)\*(P(1) + 4.0\*(EVEN + 1) + 2.0\*(A(L) + A(L+1)))  
RETURN  
END

CARC  
NUMBER

233 C  
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SUBROUTINE BETNF(N,C,BETA,J,PE)

PERDSE

TO PRODUCE AN ECUCISTANTLY TABULATED BETA-DISTRIBUTION

DESCRIPTION OF ARGUMENTS

N,C - INPUT PARAMETERS FOR THE BETA-DISTRIBUTION

FCLATIONS.

BETA - ONE-DIMENSIONAL BETA-DISTRIBUTION ARRAY PRODUCED IN

THE SUBROUTINE.

J - NUMBER OF VALUES IN BETA.

PE - ONE-DIMENSIONAL ARRAY OF P-VALUES USED IN GENERATING

THE BETA DISTRIBUTION

SUBROUTINE ACTAFIN(C,BETA,J,PE)

DOUBLE PRECISION N,C,F,PII(1),G,GAMMA,BETA(101),X,DELTA,A,B,D,E,F

COMPA DELTA

P = C.C

J = 1

DELTA = C.C

G = GAMMA\*(2.0/C+1.0/A-C+1.0)

A=DELTA\*(1.540+0.1) - .77C+22\*

IFIC .AE. 0.0) GC TC 1

IFIN .AE. 0.0) GC TC 1

NN = 4

RETA(1) = G

X = G

GO TO 15

1 IFIN .AE. C) GC TC 2

NN = 1

RETA(1) = 0.0

X = G

GO TO 15

3 NN = 3

RETA(1) = G

X = C.C

GO TO 15

2 NN = 2

RETA(1) = 0.0

X = C.C

IF J = J-1

RETA(J)=C.C

O = P + DELTA

DELTA = O

IFIN .GE. 0.1) DELTA) GC TC 45

GO TO 110.2\*(30+80\*50), NN

1\* DELTA(1)=X

F=1/2\*

IFIC .GE. 0) GC TC 15 \*

RETA(J) = G\*delc

GO TO 15

2\* A=DELTA(1)\*P \*

DELTA(1)=1+0.1 - P) \*

F=1/A \*

F=1/P \*

IFIC .GE. 0) GC TC 15

\*  $P^0 = (I \times 10^A)^0 \geq 5.4 \times 10^{-39}$

$c \log(I \times 10^A) \geq \log(5.4) - 39$

$c \geq \frac{\log(5.4) - 39}{\log(P)}$









```

C 521 FUNCTION INTER(I,J,F,YEL)
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C 579
C 580

```

FUNCTION INTER(I,J,F,YEL)  
 PURPOSE  
 TO PRODUCE A LINEAR INTERPOLATION  
 DESCRIPTION OF ARGUMENTS  
 I - COMPONENT TYPE DESIGNATION  
 J - NUMBER OF VALUES IN ARRAY IN WHICH THE NUMBER YEL IS  
 TO BE INTERPOLATED  
 F - ONE-DIMENSIONAL ARRAY FROM WHICH ELEMENTS THE INTERPOLATED  
 VALUE IS TO BE CALCULATED  
 YEL - NUMBER WHOSE CORRESPONDING VALUE IS TO BE FOUND BY  
 INTERPOLATION.

```

      DOUBLE PRECISION FUNCTION INTER(I,J,F,YEL)
      DOUBLE PRECISION C,D,X,Y,A,F,YEL,AX(100,101)
      DIMENSION A(101), F(101)
      COMMON /PLK1/ AX
      DO 100 M=1,J
      L=M
      10 C=(F(1)+1)
      IF(L.GT. J) GO TO 14
      IF(A(L)-YEL)GOTO 11,12
      11 INTERO = F(L)
      GO TO 13
      12 C = A(L) - 5(L-1)
      Y = YEL - A(L-1)
      D = F(L) - F(L-1)
      X = Y/D*0
      INTER = F(L-1) + X
      13 RETURN
      14 WRITE (5,200)
      200 FORMAT('OVERFLOW - INTERF')
      RETURN
      END
    
```

FUNCTION K(M,G,O,N1,C1)  
 PURPOSE  
 TO PRODUCE A WEIGHTING FACTOR FOR DECREASING THE LESS  
 SIGNIFICANT DATA IN G.

DESCRIPTION OF ARGUMENTS  
 N1,G,O - NUMBER OF TRIALS AND SUCCESSES FOR ANALOGOUS  
 PARAMETERS) - LESS SIGNIFICANT DATA  
 N1,C1 - NUMBER OF TRIALS AND SUCCESSES FOR ANALOGOUS  
 PARAMETERS) - MORE SIGNIFICANT DATA

```

      DOUBLE PRECISION FUNCTION K(M,G,O,N1,C1)
      DOUBLE PRECISION N1,G,O,N1,C1,A,C,BX(101),BTZ(101),BX(101),CMAREA,
      V1,B1,A1,AREA,CULT10,CX(101),F(101)
      COMMON /PLK1/
      K = 1.0
    
```

CIVIC  
NUMBER

PAGE 11

```
581 (FING SEC. NI .AND. CJ .SC. CI) GC TC 2  
582 (FING SEC. NI .OR. AI .SC. D.G) GC TC 2  
583 CALL RETRAN(CS,BIX,JJ,FB)  
584 CALL RETRAN(CI,ATZ,JJ,FB)  
585 * * * * *  
586 IF(RIZ(L) .LF. RTX(L)) GC TC 1  
587 RTX(L) = RTX(L)  
588 GO TO 100  
589 ( RTX(L) = RIZ(L)  
590 RTX(L) = RIZ(L)  
591 CMAPEA = AREAF(RX,JJ)  
592 TIAREA = AREAF(CX,JJ)  
593 K = CMAPEA/TIAREA  
594 * * * * *  
595 * * * * *  
596 * * * * *  
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\*\*\* END OF DATA \*\*\*

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13. ABSTRACT

This report documents a program for estimating overall system reliability by judiciously combining individual component data, laboratory test data and finally flight data as gathered at two different periods in time. All data used in arriving at this single reliability estimate is assumed to be attribute in nature.

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